

## **Defect Definitions**

| Description                              | Definition   | Maximum | Temperature(s)<br>tested at (°C) | Notes | Test |
|--|--|---------|----------------------------------|-------|------|
| Major dark<br>field defective<br>pixel   | Defect >= 148 mV   | 40      | 27, 40                           | 1     | 6    |
| Major bright<br>field defective<br>pixel | Defect >= 10 %   |         |                                  | 1     | 7    |
| Minor dark<br>field defective<br>pixel   | Defect >= 76 mV  | 400     | 27, 40                           |       | 6    |
| Dead pixel                               | Defect >= 80 %   | 5       | 27, 40                           | 1     | 7    |
| Saturated<br>pixel                       | Defect >= 340 mV   | 10      | 27, 40                           | 1     | 6    |
| Cluster defect                           | A group of 2 to 10 contiguous major<br>defective pixels, but no more than 2<br>adjacent defects horizontally | 8       | 27, 40                           | 1     |      |
| Column<br>defect                         | A group of more than 10 contiguous<br>major defective pixels along a single<br>column                        | 0       | 27, 40                           | 1     |      |

Notes:

1. There will be at least two non-defective pixels separating any two major defective pixels.

## Defect Map

The defect map supplied with each sensor is based upon testing at an ambient (27°C) temperature. Minor point defects are not included in the defect map. All defective pixels are reference to pixel 1,1 in the defect maps.